



## **Mini-workshop on Advanced Characterization Techniques in Materials Science**

10<sup>th</sup> of March 2010, 10:30 am  
Auditorium of Instituto Tecnológico e Nuclear (ITN)  
Estrada Nacional 10, Sacavém

**10:30 Opening**

**Vanya Darakchieva**, *Instituto Tecnológico e Nuclear/CFNUL*

**10:40 Generalized Terahertz to Ultraviolet ellipsometry in contemporary Semiconductor and Nanostructure research: Sculptured hybrid nanostructure thin films and sheet carrier characterization in InN and graphene**

**Mathias Schubert**, *University of Nebraska-Lincoln*

**11:30 Metal contamination detection by spectroscopic ellipsometry in nickel induced crystallized silicon films**

**Luis Pereira**, *CENIMAT, FCT, Universidade Nova de Lisboa*

**11:50 Emission channeling in wide band gap semiconductors**

**Ulrich Wahl**, *Instituto Tecnológico e Nuclear*

**12:20 Lunch Break**

**14:00 Valence band maximum determination using XPS: the problems and solutions**

**Nenad Budaleski**, *Centro de Física e Investigação Tecnológica, Universidade Nova de Lisboa*

**14:20 Influence of thermal annealing on structural and optical properties of GaN/AlN quantum dot superlattices**

**Teresa Monteiro**, *Departamento de Física e I3N, Universidade de Aveiro*

**14:40 Rare earth doped nitrides for light emission from IR to UV**

**Katharina Lorenz**, *Instituto Tecnológico e Nuclear*

**15:10 Coffee Break**

**15:30 Lab tour**

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For further information please contact Vanya Darakchieva, ITN, [vanya@itn.pt](mailto:vanya@itn.pt)